



## Features

- Drain-Source Breakdown Voltage  $V_{DSS}$  - 20 V
- Drain-Source On-Resistance
  - $R_{DS(ON)}$  30m $\Omega$ , at  $V_{GS} = -4.5V$ ,  $I_{DS} = -4.7A$
  - $R_{DS(ON)}$  35m $\Omega$ , at  $V_{GS} = -2.5V$ ,  $I_{DS} = -4.1A$
  - $R_{DS(ON)}$  40m $\Omega$ , at  $V_{GS} = -1.8V$ ,  $I_{DS} = -2.0A$
- Continuous Drain Current at  $T_A=25^\circ C$   $I_D = -4.2A$
- Advanced high cell density Trench Technology
- RoHS Compliance & Halogen Free

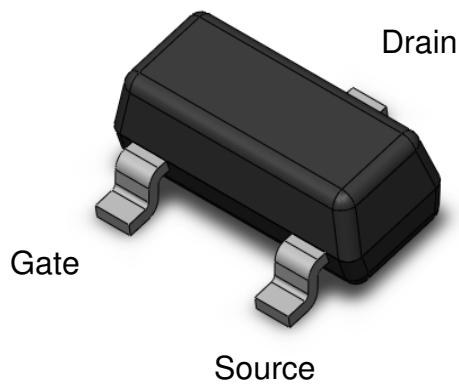
## Applications

- Power Management
- Portable Equipment
- Battery Powered System
- DC/DC Converter

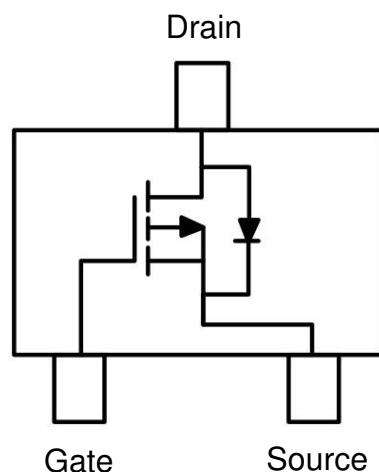
## Description

The CT2323-R3 uses high performance Trench Technology to provide excellent  $R_{DS(ON)}$  and low gate charge which is suitable for most of the synchronous buck converter applications .

## Package Outline



## Schematic





CT2323-R3

## P-Channel Enhancement MOSFET

### Absolute Maximum Rating at 25°C

Symbol	Parameters	Ratings	Units	Notes
$V_{DS}$	Drain-Source Voltage	-20	V	
$V_{GS}$	Gate-Source Voltage	$\pm 8$	V	
$I_D$	Continuous Drain Current @ $T_A=25^\circ\text{C}$	-4.7	A	1
$I_{DM}$	Pulsed Drain Current	-6.8	A	1
$P_D$	Total Power Dissipation @ $T_A=25^\circ\text{C}$	1.35	W	2
$T_{STG}$	Storage Temperature Range	-55 to 150	°C	
$T_J$	Operating Junction Temperature Range	-55 to 150	°C	

### Thermal Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$R_{\Theta JA}$	Thermal Resistance Junction-Ambient ( $t=10\text{s}$ )		-	200	-	°C /W	1,4



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Electrical Characteristics  $T_A = 25^\circ\text{C}$  (unless otherwise specified)

## Static Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$B_{VDSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$ , $I_D = -250\mu\text{A}$	-20	-	-	V	
$I_{DSS}$	Drain-Source Leakage Current	$V_{DS} = -20\text{V}$ , $V_{GS} = 0\text{V}$	-	-	-1	$\mu\text{A}$	
$I_{GSS}$	Gate-Source Leakage Current	$V_{GS} = \pm 8\text{V}$ , $V_{DS} = 0\text{V}$	-	-	$\pm 100$	nA	

## On Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$R_{DS(\text{ON})}$	Drain-Source On-Resistance	$V_{GS} = -4.5\text{V}$ , $I_D = -4.7\text{A}$	-	30	39	m	Fig 4
		$V_{GS} = -2.5\text{V}$ , $I_D = -4.1\text{A}$	-	35	52	m	
		$V_{GS} = -1.8\text{V}$ , $I_D = -2.0\text{A}$	-	45	68	m	
$V_{GS(\text{TH})}$	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = -250\mu\text{A}$	-0.4	-	-1.0	V	Fig 5

## Dynamic Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$C_{iss}$	Input Capacitance	$V_{DS} = -15\text{V}$ , $V_{GS} = 0\text{V}$ , $f = 1\text{MHz}$	-	1773	-	pF	Fig 3
$C_{oss}$	Output Capacitance		-	178	-		
$C_{rss}$	Reverse Transfer Capacitance		-	140	-		

## Switching Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$T_{D(\text{ON})}$	Turn-On Delay Time	$V_{DS} = -15\text{V}$ , $V_{GS} = -10\text{V}$ , $R_G = 6\Omega$ , $I_D = -1.0\text{A}$	-	4.75	-	ns	Fig 11 & 12
$T_R$	Rise Time		-	21	-		
$T_{D(\text{OFF})}$	Turn-Off Delay Time		-	39	-		
$T_F$	Fall Time		-	20.5	-		
$Q_G$	Total Gate Charge	$V_{DS} = -15\text{V}$ , $V_{GS} = -10\text{V}$ , $I_D = -4.2\text{A}$	-	21	-	nC	Fig 9 & 10
$Q_{GS}$	Gate-Source Charge		-	2.8	-		
$Q_{GD}$	Gate-Drain (Miller) Charge		-	4.1	-		



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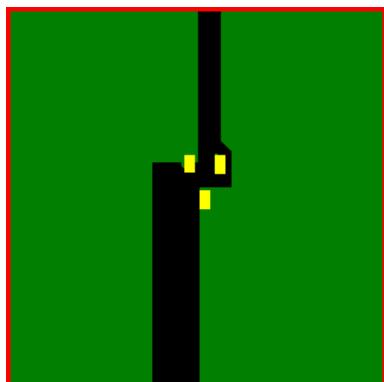
## P-Channel Enhancement MOSFET

### Drain-Source Diode Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$V_{SD}$	Body Diode Forward Voltage	$V_{GS} = 0V, I_D = -1.0$			1.2	V	
$I_{SD}$	Body Diode Continuous Current				-4.2	A	1

Note:

1. The power dissipation is limited by 150°C junction temperature.
2. Device mounted on a glass-epoxy board



FR-4  
25.4 × 25.4 mm .  
2 Oz Copper

Test Board

3. The data tested by pulsed , pulse width  $\leq 300\mu s$  , duty cycle  $\leq 2\%$
4. Thermal Resistance follow JESD51-3.



## Typical Characteristic Curves

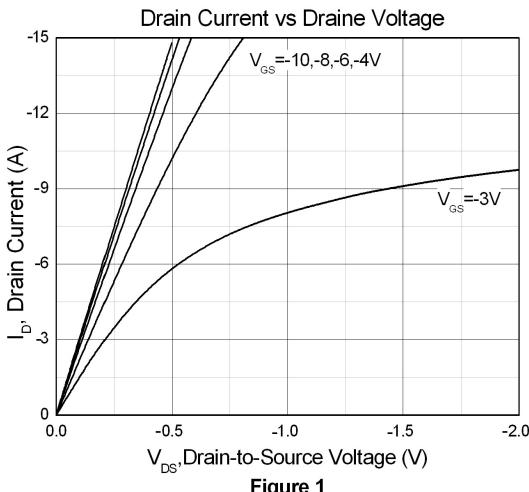


Figure 1

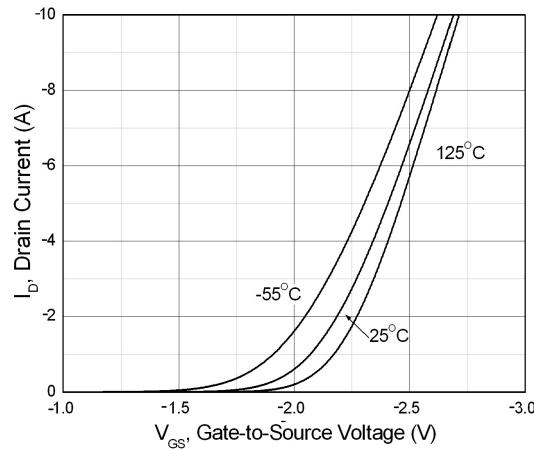


Figure 2

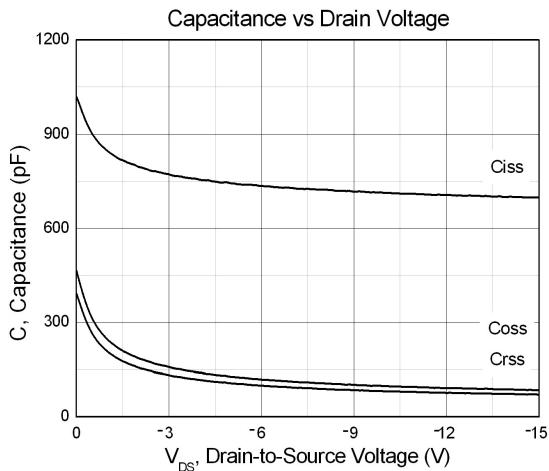


Figure 3

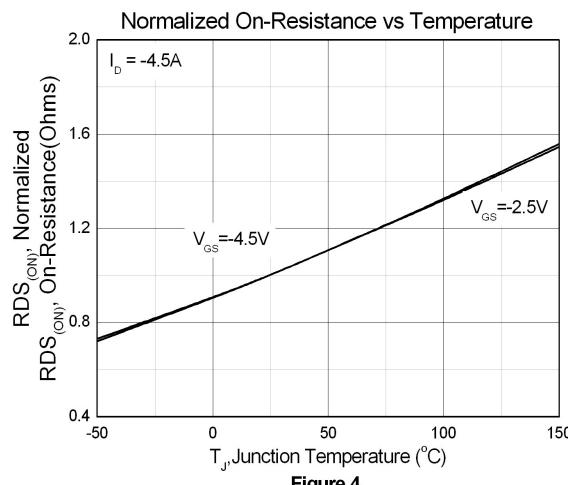


Figure 4

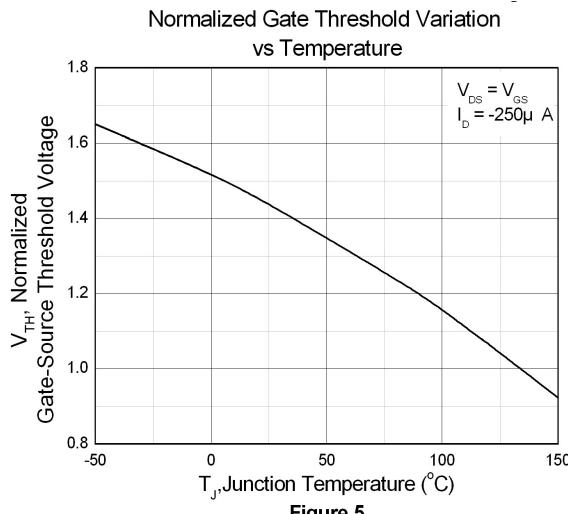


Figure 5

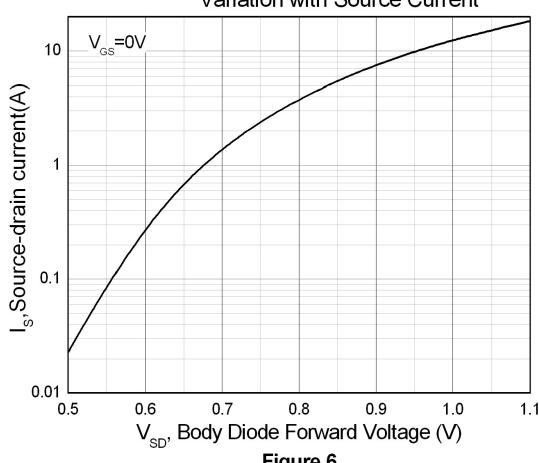
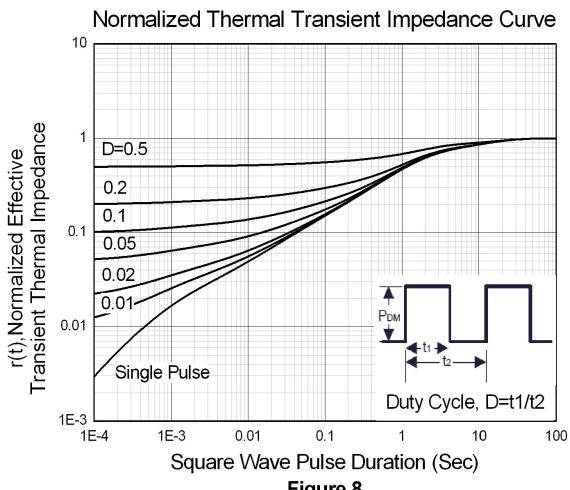
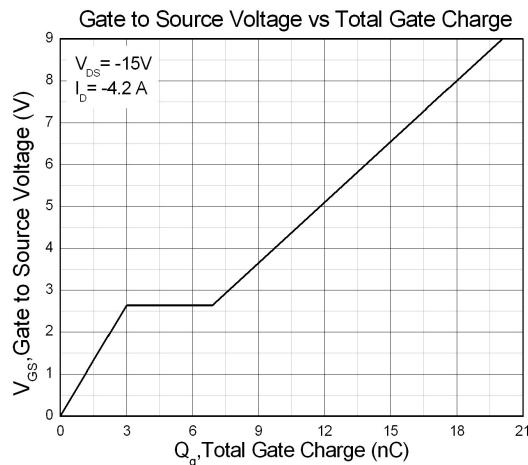


Figure 6



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## P-Channel Enhancement MOSFET





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### Test Circuits & Waveforms

Figure 9: Gate Charge Test Circuit

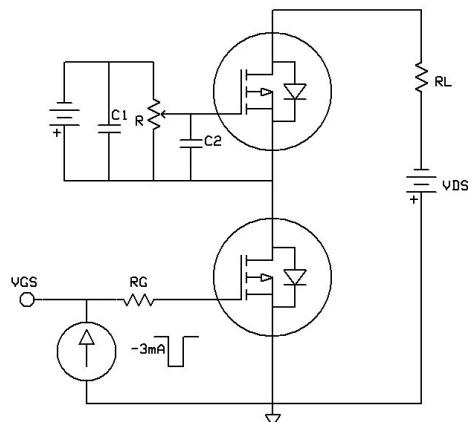


Figure 10: Gate Charge Waveform

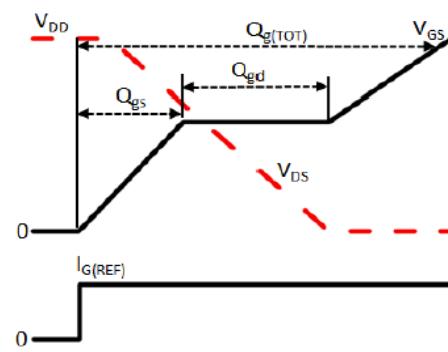


Figure 11: Switching Time Test Circuit

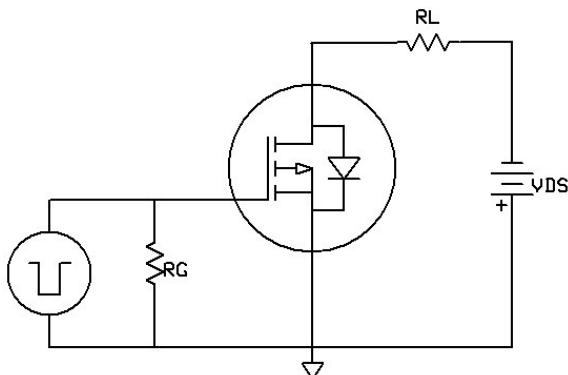
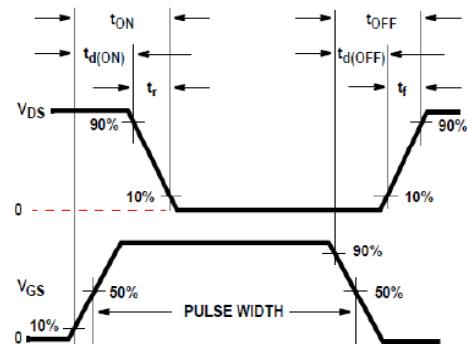


Figure 12: Switching Time Waveform

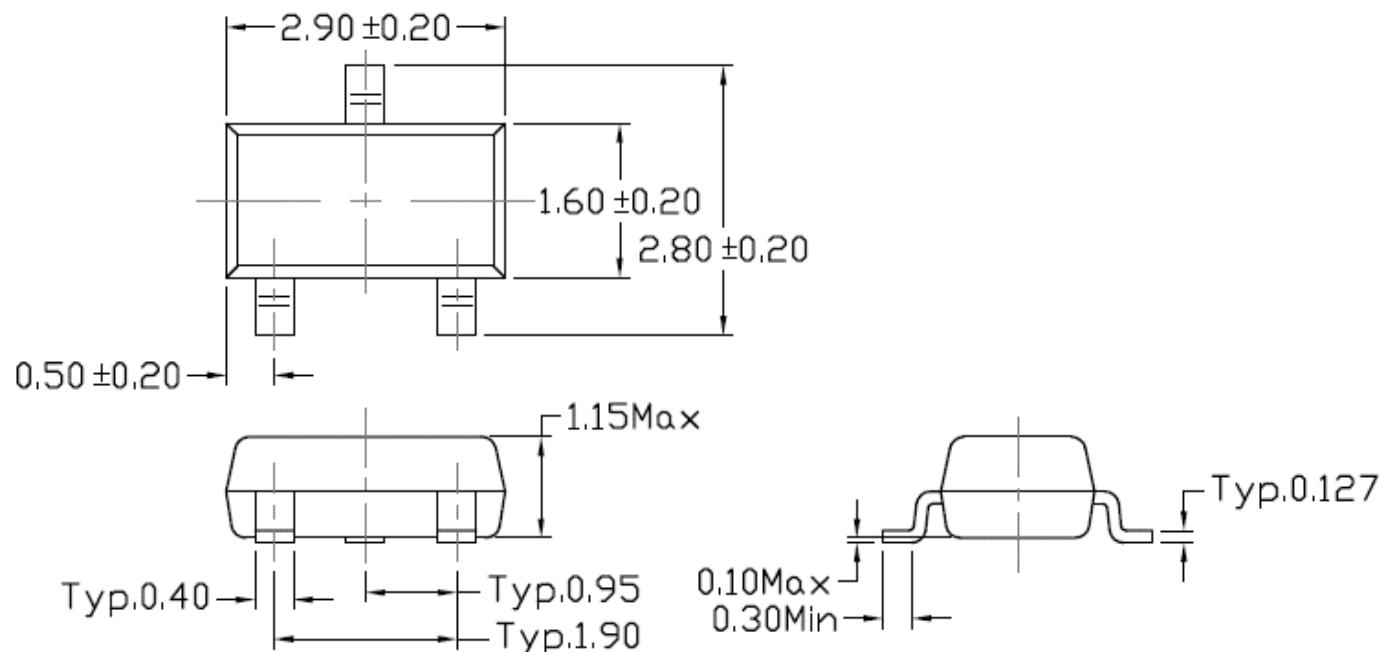




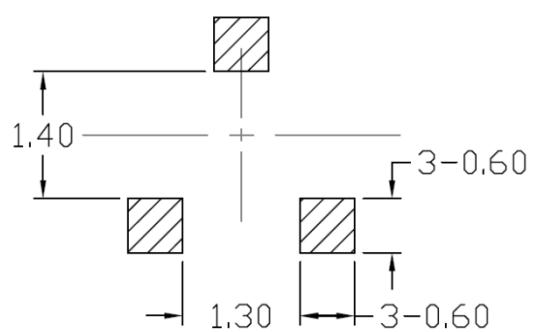
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## P-Channel Enhancement MOSFET

### Package Dimension (SC-59)



### Recommended pad layout for surface mount leadform

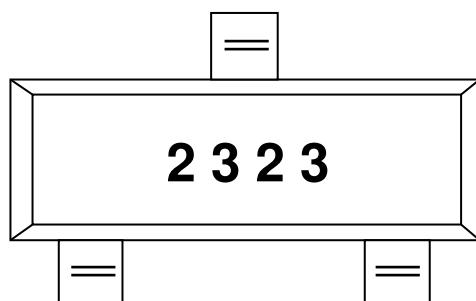




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## Marking Information



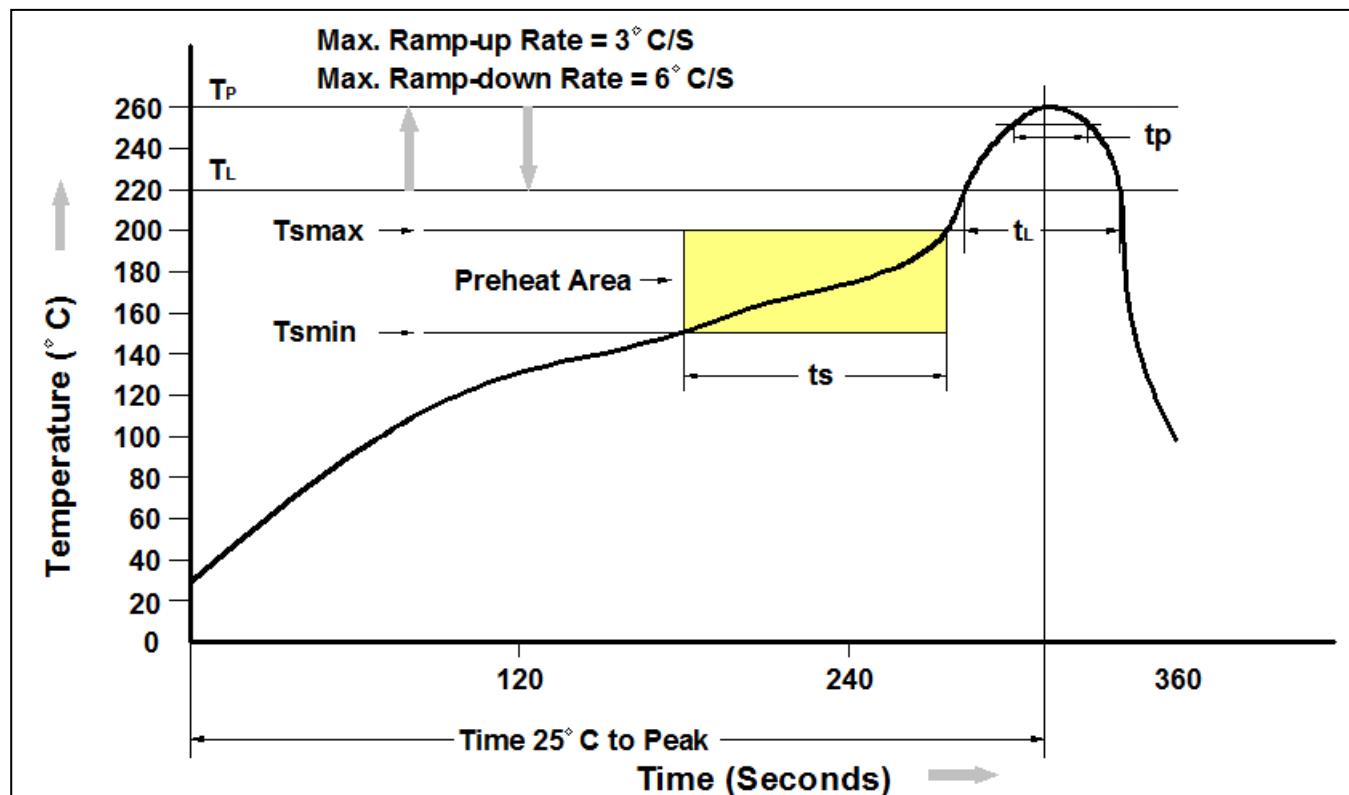
2323 : Device Number

## Ordering Information

<i>Part Number</i>	<i>Description</i>	<i>Quantity</i>
CT2323-R3	SC-59 Reel	3000 pcs



## Reflow Profile



Profile Feature	Pb-Free Assembly Profile
Temperature Min. (T <sub>smin</sub> )	150 °C
Temperature Max. (T <sub>smax</sub> )	200 °C
Time (t <sub>s</sub> ) from (T <sub>smin</sub> to T <sub>smax</sub> )	60-120 seconds
Ramp-up Rate (t <sub>L</sub> to t <sub>P</sub> )	3°C/second max.
Liquidous Temperature (T <sub>L</sub> )	217°C
Time (t <sub>L</sub> ) Maintained Above (T <sub>L</sub> )	60 – 150 seconds
Peak Body Package Temperature	260 °C +0 °C / -5 °C
Time (t <sub>P</sub> ) within 5 °C of 260 °C	30 seconds
Ramp-down Rate (T <sub>P</sub> to T <sub>L</sub> )	6°C/second max
Time 25 °C to Peak Temperature	8 minutes max.



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**CT2323-R3**

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